Heterogeneous Integration Technologies for High-Temperature, High-Density, Low-Profile Power Modules

of Wide Bandgap Devices in Electric-Drive Applications



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Project Overview

Timeline

- Project start date: April 1st, 2019
- Project end date: March 31st, 2024
- Percent complete: 40%

Budget

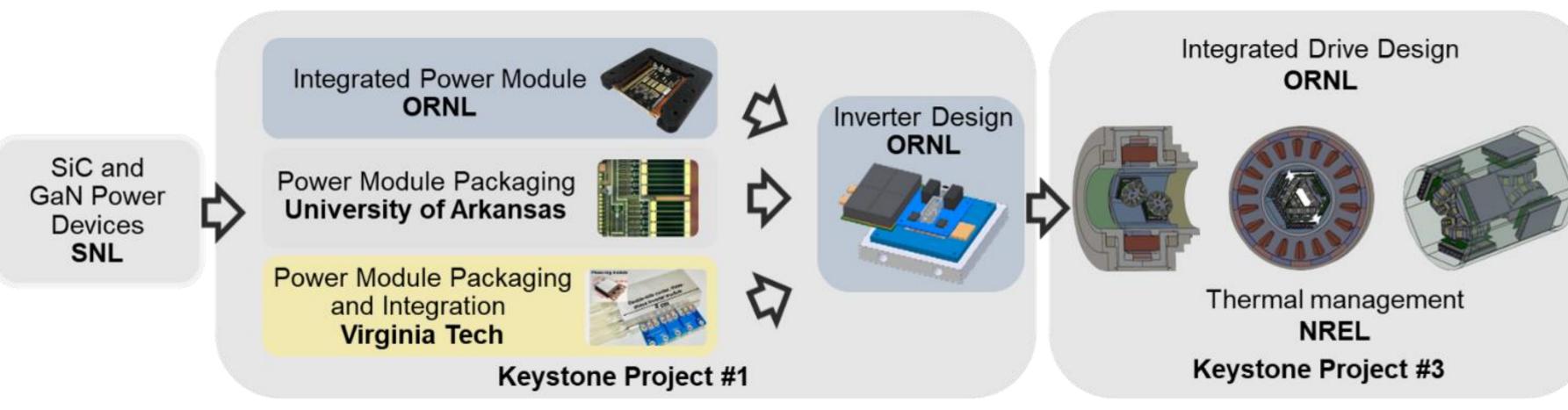
- Total project funding: \$1.5 M
- Funding for FY 2020: \$0.3 M
- Funding for FY 2021: \$0.3 M

Barriers and Technical Targets

- > Materials: high-performance bonding materials and assembly technologies (planar, double-side cooling) for making high-temperature (> 200 °C) power modules to enable high converter power density (> 100 kW/L);
- > Gate Driver: high-temperature (> 200 °C) intelligent gate driver with integrated current sensor and EMI mitigation.

Relevance and Objectives

- Goal: Develop packaging materials, assembly processes, and circuit technologies for making WBG power modules with double-side cooling capability, intelligent gate driver, and integrated EMI mitigation solutions.
- > Impact: Enable the EDT consortium to achieve its targets on performance, cost, power density, and reliability of a 100 kW traction drive system.
- Project Objectives
 - Develop a low-cost packaging technology for making double-side cooled WBG (SiC/GaN) power modules with parasitic inductances < 5 nH, heat flux density > 400 W/cm², and working junction temperature > 200 °C;
 - Design and prototype > 200 °C gate drivers with parasitic-inductance based current sensor and protection for module integration.



Approach

- > Proposed Research: Design, fabrication, and testing of planar WBG power modules and their integration with gate drivers for electric drives.
- > Technology Summary: Low parasitic & double-side cooled module fabrication; interconnection by silver-sintering; parasitic-inductance based current sensor integrated in gate driver; air-core transformer for driver power supply.
- > Challenges & Opportunities: Prototyping yield for design verification; through materials and assembly engineering \rightarrow low-cost manufacturing.

Technical Accomplishments Cree chip: (1.2 kV, 149 A, 13 mΩ) Power Module Packaging Prototypes delivered to ORNL Potential for higher Static, dynamic, and thermal testing (passed) temperature Gate Driver and Current Sensor Gate driver for the segmented inverter at ORNL **Parasitic Inductance-Based Current Sensor** Connectors to daughter board Motherboard Output ___ temperature **Daughter board Power Supply with Air-Core Transformer Testing waveforms Class-E with Constant Current** V_{ds} peak: 25 V OZVS Efficiency and Loss Breakdown Switching device and capacito ZVS at all load conditions;

Constant output current;

Improved efficiency with air-core input inductor.

Collaboration

ORNL: G-J Su, E. Gurpinar, & B. Ozpineci, inverter NREL: P. Paret & S. Narumanchi, reliability **INREL** Dowa: S. Yuki, substrate DOWA UArk: A. Mantooth, HT gate driver chip SUNY-Poly: W. Sung, SiC power device

Summary

- Relevance: enable the EDT consortium to achieve its targets on performance, cost, power density, and reliability of a 100 kW traction drive system.
- Approach: research, develop, and evaluate the integration and packaging technologies for making hightemperature, high-density, and low-profile wide-bandgap (WBG) power electronics modules with intelligent gate driver, current sensor, and EMI mitigation.
- **Deliverables:**
- A minimum of six working prototypes of double-side cooled SiC (1.2 kV, 149 A, 13 mΩ) phase-leg modules and a minimum of six gate drivers to ORNL for the team's construction of a 100 kW, segmented inverter;
- Module design and simulation results, materials processing conditions, assembly procedures, and testing data to DOE and potential module manufacturers;
- Circuit design, simulation results, and bill of materials for making gate drivers with parasitic-inductance based current sensor to DOE;
- Circuit design, simulation results, and bill of materials for making gate driver power supply with air-core transformer to DOE.

Next Steps

- Reliability evaluation of the double-side cooled modules;
- Selection and evaluation of high-temperature encapsulation materials;
- > Fine-tuning of the current sensor for compensating the temperature effect;
- Selection and testing of high-temp components for constructing the gate-driver power supply.

^{*} This presentation does not contain any proprietary, confidential, or otherwise restricted information. * Any proposed future work is subject to change based on funding levels.